

CERTIFICATION TEST REPORT

Report Number.: 4789468331-E10V2

Applicant: SAMSUNG ELECTRONICS CO., LTD.

129 SAMSUNG-RO, YEONGTONG-GU, SUWON-SI,

GYEONGGI-DO, 16677, KOREA

Model : SM-N986B/DS, SM-N986B

FCC ID : A3LSMN986B

EUT Description: GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax,

UWB, WPT and NFC

Test Standard(s): FCC 47 CFR PART 1 SUBPART I

FCC 47 CFR PART 2 SUBPART J

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REPORT REVISION HISTORY

Rev.	Issue Date	Revisions	Revised By
V1	06/23/20	Initial issue	Sungeun Lee
V2	06/29/20	Updated to address TCB's question	Sungeun Lee

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1. ATTESTATION OF TEST RESULTS

COMPANY NAME: SAMSUNG ELECTRONICS CO., LTD.

EUT DESCRIPTION: GSM/WCDMA/LTE Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax,

UWB, WPT and NFC

MODEL: SM-N986B/DS, SM-N986B

SERIAL NUMBER: R3CN40CD4FP (RADIATED);

DATE TESTED: JUN 18, 2020;

APPLICABLE STANDARDS

STANDARD TEST RESULTS

FCC PART 1 SUBPART I FCC PART 2 SUBPART J

Complies

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

Approved & Released For UL Korea, Ltd. By:

Tested By:

Junwhan Lee Suwon Lab Engineer UL Korea, Ltd. Sungeun Lee Suwon Lab Engineer UL Korea. Ltd.

2. TEST METHODOLOGY

All calculations were made in accordance with FCC OET Bulletin 65 Edition 97-01.

3. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro
Shield Room 1

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf.

4. EQUIPMENT UNDER TEST

4.1. DESCRIPTION OF EUT

The EUT has WPT (Wireless Power Transfer) feature which has inductive charging coil to charge phone or watch. The charging frequency is between 110 kHz to 148 kHz, and the maximum power consumption is 9.0 W in charging status.

This report covers the Samsung models SM-N986B/DS and SM-N986B. These models are identical in hardware except SM-N986B has single SIM tray. With some pre-scan, model SM-N986B/DS was set for final test.

4.2. WORST-CASE CONFIGURATION

Test configuration	Description	
DUT to Phone test configuration 1	Charging from Phone to DUT	
DUT to Phone test configuration 2	Charging from Phone to DUT (TA Charging from DUT)	
DUT to Phone test configuration 3	Charging from Phone to DUT	
DUT to Phone test configuration 4	Charging from Phone to DUT (TA Charging from DUT)	
DUT to Watch test configuration 5	Charging from Watch to DUT	
DUT to Watch test configuration 6	Charging from Watch to DUT (TA Charging from DUT)	

Note:

Configuration 2, 4 and 6 were tested with the worst case of configuration 1, 3 and 5.

4.3. KDB 680106 D01 v03 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device
(1) Power transfer frequency is less than 1 MHz.	Yes. Operating Frequency is between 110kHz to 148 kHz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field at 15 cm from the device are 4.48 % of the FCC H field limit.

4.4. DESCRIPTION OF TEST SETUP

SUPPORT EQUIPMENT & PERIPHERALS

SUPPROT EQUIPMENT & PERIPHERALS LIST							
Description	Manufacturer	Model	Serial Numver	FCC ID			
Phone	Samsung Electronics Co., Ltd.	SM-G986B/DS	R3CMB0C70XN	A3LSMG986B			
Watch Samsung Electronics Co., Ltd.		SM-R835F	RFAM90ZXFTF	A3LSMR835			
Traver Adapter	Samsung Electronics Co., Ltd.	EP-TA800	R37N47V0G92HM3	DoC			
USB Data Cable Samsung Electronics Co., Ltd. EP-DG980 -							

TEST SETUP

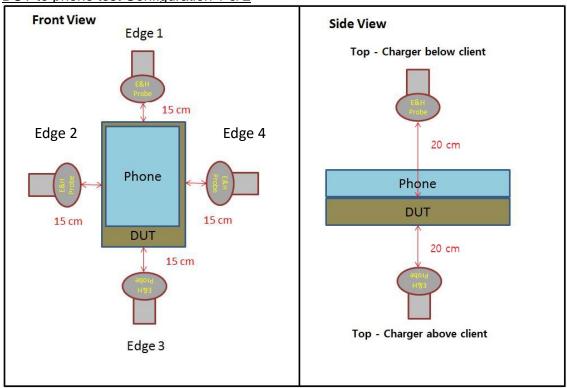
The following three modes are tested in test configurations;

Mode
Operating (SUPPORT Equipment, <10% Power Charging)
Operating (SUPPORT Equipment, 50~55% Power Charging)
Operating (SUPPORT Equipment, 90~95% Power Charging)

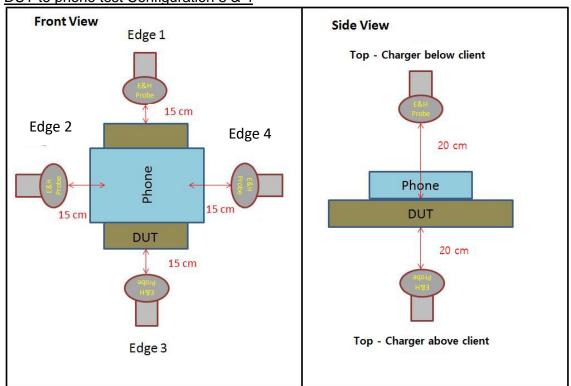
MEASUREMENT TEST SETUP

The measurement was taken using a probe placed 15 cm surrounding the device and 20 cm above the top surface of the EUT. Measurements were taken the top (charger below/above client) and all sides of the EUT per KDB680106 D01 v03 and RF Exposure Procedures (Wireless Power Transfer) in TCB Workshop October, 2018.

DUT to phone test Configuration 1 & 2



DUT to phone test Configuration 3 & 4



DUT to Watch test Configuration 5 & 6 **Front View Side View** Edge 1 Top - Charger below client 15 cm Edge 4 Edge 2 Watch 20 cm 15 cm 15 cm Watch DUT DUT 15 cm Edge 3

5. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report;

Test Equipment List							
Description Manufacturer Model Serial Numver Cal Date Cal Due							
Electric and Magnetic Field Probe	Narda	EHP-200AC	170W X91008	3-2-2020	3-2-2021		

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6. Maximum PERMISSIBLE RF EXPOSURE

FCC LIMITS AND SUMMARY

6.1.1. FCC LIMITS

§ 1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in § 1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of § 2.1093 of this chapter.

TABLE 1-LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)				
(A) Lim	its for Occupational	/Controlled Exposu	res					
0.3–3.0	614	1.63	*(100)	6				
3.0–30	1842/f	4.89/f	*(900/f ²)	6				
30–300	61.4	0.163	1.0	6				
300–1500			f/300	6				
1500–100,000			5	6				
(B) Limits	(B) Limits for General Population/Uncontrolled Exposure							
0.3–1.34	614	1.63	*(100)	30				
1.34–30	824/f	2.19/f	*(180/f ²)	30				

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300–1500 1500–100,000			f/1500 1.0	30 30

f = frequency in MHz

* = Plane-wave equivalent power density

NoTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their
employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure.

Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occu-

pational/controlled limits apply provided he or she is made aware of the potential for exposure.

Note 2 to Table 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

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6.2. TEST RESULTS

6.2.1. FCC RF EXPOSURE

H-FIELD MEASUREMENTS

Note: Peak measurement were performed. RMS values were calculated from the peak measurement.

Please refer to the formula for calculating the RMS values: [Field Strength x $\sqrt{\text{Duty Cycle}}$]. Additional test was performed in each Test mode by moving the probe surrounding the device to find the maximum exposure.

TEST results of DUT to phone test Configuration 1 & 2

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
			Top - charger above client		0.017
			Top - charger below client]	0.018
			Edge 1		0.017
	Operating Real Product (Power <10% charging)		Edge 2		0.017
	(i one: 110/0 enaiging)		Edge 3	Top - charger below client Edge 1 0.017 Edge 2 0.017 Edge 3 0.018 Edge 4 0.023 max Top - charger above client Top - charger below client Edge 1 Edge 2 0.018 Top - charger below client Edge 1 0.018 Edge 2 0.018 Edge 3 1.63 0.021 Edge 4 0.018 Top - charger above client 0.017 0.018 0.018 0.021 0.018 0.024 0.018	
			Edge 4		
			max		0.025
			Top - charger above client		
			Top - charger below client		0.017
		45	Edge 1		0.018 0.023 0.025 0.018 0.017 0.018 0.018 0.021 0.018 0.024 0.018 0.018
Configuration 1	Operating Real Product (Power 50~55% charging)	15 cm probe to edges of EUT	Edge 2	1.63 0.021	0.018
	(, , , , , , , , , , , , , , , , , , ,	and	Edge 3		0.021
		20 cm probe to top surface of the EUT	Edge 4		0.018
		Surface of the Lot	max		0.018 0.018 0.021 0.018 0.024 0.018
			Top - charger above client	0.018	0.018
			Top - charger below client		0.018
			Edge 1		0.018
	Operating Real Product (Power 90~95% charging)		Edge 2		0.019
	(. 133. 00 0070 s.i.a. girig)		Edge 3		0.022
			Edge 4		0.018
			max		0.023
Configuration 2	Operating Real Product]	Edge 2		0.026
Comiguration 2	(Power <10% charging)		max		0.029

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TEST results of DUT to phone test Configuration 3 & 4

FCC RF Exposure Result						
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)	
			Top - charger above client		0.019	
			Top - charger below client		0.033	
			Edge 1		0.017	
	Operating Real Product (Power <10% charging)		Edge 2		0.017	
	(* 2		Edge 3 Edge 4 max Top - charger above client Top - charger below client Edge 1 Edge 2 Edge 3 1.63 Edge 4 max		0.034	
			Edge 4		0.021	
			max		0.036	
			Top - charger above client		0.020	
				0.036		
		45		Edge 3 0.03 Edge 4 0.02 max 0.03 rger above client 0.02 Edge 1 0.02 Edge 2 0.03 Edge 3 1.63 0.02 Edge 4 0.06 max 0.06 rger above client 0.06 rger above client 0.06		0.021
Configuration 3	Operating Real Product (Power 50~55% charging)	15 cm probe to edges of EUT	Edge 2		0.030	
	(1 oviol do do // charging/	and	Edge 3		0.021	
		20 cm probe to top surface of the EUT	Edge 4		0.062	
		ouridos or the Est	max		0.065	
			Top - charger above client	0.022		
			Top - charger below client		0.028	
	0 " 0 10 1		Edge 1		0.027	
	Operating Real Product (Power 90~95% charging)		Edge 2		0.053	
	,		Edge 3		0.030	
			Edge 4		0.045	
			max		0.050	
Configuration 4	Operating Real Product		Edge 2		0.049	
Comgulation 4	(Power 50~55% charging)		max		0.067	

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TEST results of DUT to phone test Configuration 5 & 6

FCC RF Exposure Result						
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)	
Configuration 5	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger below client	1.63	0.024	
			Edge 1		0.048	
			Edge 2		0.042	
			Edge 3		0.036	
			Edge 4		0.069	
			max		0.071	
	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.031	
			Edge 1		0.033	
			Edge 2		0.042	
			Edge 3		0.061	
			Edge 4		0.028	
			max		0.062	
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.030	
			Edge 1		0.021	
			Edge 2		0.022	
			Edge 3		0.047	
			Edge 4		0.035	
			max		0.049	
Configuration 6	Operating Real Product (Power <10% charging)		Edge 2		0.044	
			max		0.073	

6.2.2. FCC SUMMARY OF RESULTS

H-Field Limit					
FCC RF Exposure	Maximum meas data (A/m)	Percentage (%)			
1.63	0.073	4.48			
Conclusion:					

H-Field result is less than 50% of the MPE limit.

END OF TEST REPORT